

386-1, Ho-Dong, Yongin-City, Kyungki-Do, Korea 449-100
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#### **EMC TEST REPORT For FCC**

Test Report No. : 2004050015

Date of Issue : June 4, 2004

Model/Type No. : Digimax V50

Kind of Product : Digital Camera

Applicant : Samsung Techwin Co., Ltd.

Applicant Address : 145-3 Sangdaewon 1 dong, Chungwon-ku, Sungnam City,

Kyungki-do, Korea

Manufacturer : 1) Samsung Techwin Co., Ltd.

2) Tianjin Samsung Opto-Electronics Co., Ltd.

Manufacturer Address : 1) 42, Sungju-dong, Changwon City, Kyungnam, Korea

2) 7 Pingchang Road, Nankai Dist., Tianjin, China

Contact Person : Hyung-Moo, Huh (Engineer)

Telephone : +82-31-740-8274

Received Date : May 15, 2004

Test period : Start: May 26, 2004 End: May 26, 2004

Test Results : In Compliance Not in Compliance

The test results presented in this report relate only to the object tested.

CERTITEK Standards Laboratory Co., Ltd. is accredited by Korea Laboratory Accreditation Scheme (KOLAS) which signed the International Laboratory Accreditation Cooperation (ILAC) Mutual Recognition Arrangement (MRA) for the above test item(s) and test method(s).

Tested by

Reviewed by

Young-Joon, Park EMC Test Engineer

Date: June 4, 2004

James Hong

EMC Technical Manager

Date: June 4, 2004

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#### REPORT REVISION HISTORY

Date	Revision	Page No
June 4, 2004	(2004050015) Issued	All

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#### 1.0 **General Product Description**

#### 1.0.1 Tested Equipment $\boxtimes$ Unless otherwise indicated, all tests were conducted on Model Digimax V50. Tests performed on Model \_\_\_\_\_ were considered to be representative of Model(s) \_\_\_\_\_. 1.0.2 Equipment Size, Mobility and Identification Dimensions: 105.5 (W) by 54.6 (H) by 38.0 (D) $\square$ mm $\square$ in Mobility: Serial No.: Proto-type 1.0.3 Electrical Ratings Adapter - AC 100-250V, 50/60Hz Input: EUT - DC 5V Adapter - DC 5V, 2.0A Output: EUT - Not applicable 1.0.4 Test Voltage & Frequency (Using the adapter)

Unless indicated otherwise on the individual data sheet or test results, the test voltage and frequency was as indicated below.

120Vac Voltage: 60Hz Frequency:

#### 1.0.5 Clock & Other Frequencies Utilized

12.0MHz, 27.0MHz, 54.0MHz, 32.768KHz

#### 1.1 **Model Differences**

Not applicable

#### 1.2 **Device Modifications**

The following modifications were necessary for compliance: Not applicable

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## 1.3 EUT Configuration(s)

See Appendix A for individual test set-up configuration(s). The following peripheral devices and/or interface cables were connected during the measurement:

Peripheral Devices

Device	Manufacturer	Model No.	Serial No.	FCC ID or DoC	
Personal Computer	Hewlett-Packard Company	PD1059P	-	DoC	
LCD monitor	TIANJIN SAMSUNG ELECTRONICS DISPLAY	176T-DZ/KOR	N372HVEX225526	DoC	
Adapter(1)	Anam Instruments (Shen Zhen) Co., Ltd.	AP04214-UV	0312103885AC	-	
PRINTER	Seiko Epson	Stylus Color 460	BWCE136524	DoC	
Keyboard	SAMSUNG	SEM-DT35	3T011297	DoC	
Serial Mouse	Microsoft	BASM1	4476266-20000	DoC	
Mouse (PS/2 type)	SAMSUNG	OMS3CB	0303009875	DoC	

#	Description	Ferrite Core	Length (m)	Other Details
1	AC power cable, Unshielded	No	1.8	Connect to AC power
2	AC power cable, Unshielded	No	1.8	Connect to AC power
3	AC power cable, Unshielded	No	1.8	Connect to AC power
4	AC power cable, Unshielded	No	1.8	Connect to AC power
5	Adapter(1) Output Cable, Unshielded	Yes	1.5	Between EUT and Adapter(1)
6	Adapter(2) Output Cable, Unshielded	Yes	1.5	Between LCD Monitor and PC
7	EUT USB Cable, Shielded	Yes	1.5	Between EUT and PC
8	Monitor cable, Shielded	Yes	1.8	Between the PC and Monitor
9	Printer cable, Shielded	Yes	1.8	Between the PC and Printer
10	Serial Mouse Cable, Shielded	No	1.8	Connect to Notebook PC
11	Keyboard cable, Shielded	No	1.5	Connect to Notebook PC
12	PS/2 Mouse Cable, Shielded	No	1.5	Connect to Notebook PC

# 1.4 Test Software □ Pinging □ Not applicable 1.5 EUT Operating Mode(s) Equipment under test was operated during the measurement under the following conditions: □ Test program (H-Pattern) □ Standby □ Test program (color bar) □ Test program (customer specific) □ Practice operation: USB downloading mode AV output monitoring mode

### 1.6 Calibration Details of Equipment Used for Measurement

Test equipment and test accessories are calibrated on regular basis. The maximum time between calibrations is one year or what is recommended by the manufacturer, whichever is less. All test equipment calibrations are traceable to the Korea Research Institute of Standards and Science (KRISS), therefore, all test data recorded in this report is traceable to KRISS.

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### 1.7 Test Facility

The measurement facility is located at 386-1, Ho-Dong, Yongin-City, Kyungki-Do, Korea 449-100. The sites are constructed in conformance with the requirements of ANSI C63.7, ANSI C63.4 and CISPR Publication 22.

#### 1.8 Measurement Procedure

Preliminary AC power line conducted emissions tests were performed shielded room. To find worst mode, several typical mode and typical cable position were tested. Final AC power line conducted emissions test was performed shielded room. (location is same as Preliminary test)

Based on the preliminary tests of the EUT, final test was proceeded worst case test mode and cable configuration.

Preliminary radiated emissions test were performed anechoic chamber (Distance of antenna and EUT was 3 m). To find worst mode, several typical mode and typical cable position were tested and peak level and frequency were recorded.

Final radiated emissions test was performed Open Area Test Site. Based on the preliminary tests of the EUT, final test was proceeded worst case test mode and cable configuration.

\* Measurement procedures was In accordance with ANSI C63.4-2001 7.2.3, 7.2.4, 8.3.1.1, 8.3.1.2

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## 1.9 Laboratory Accreditations and Listings

Country	Agency	Scope of Accreditation	Logo
USA	FCC	3 and 10 meter Open Area Test Sites to perform FCC Part 15/18 measurements.	FC 93250
JAPAN	VCCI	10 meter Open Area Test Site and one conducted site.	<b>P</b> -948, C-986
KOREA	MIC	EMI (CE, RE) EMS (ESD, Burst, RS, Surge, CS, Power-Frequency Susceptibility, Voltage Dips and Short Interruptions)	No. 51, KR0025
International	KOLAS	EMC	KOLAS NO.119
Europe	GLAS	EMC EN 55011, EN 55022, EN 55024, EN 61326, EN 50130-4, EN 50081-1, EN 50081-2, EN 50082-1, EN 50082-2, EN 61000-6-2, EN 61000-4-2, EN 61000-4-3, EN 61000-4-4, EN 61000-4-5, EN 61000-4-6, EN 61000-4-8, EN 61000-4-11, EN 61000-3-2, EN 61000-3-3	<b>TÜV</b> No.13000796-02

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## 2.0 Emissions Test Regulations

The emissions tests were performed according	to following regulations	<b>S</b> :
☐ EN 50081-1:1992 ☐ EN 61000-6-3:2001	☐ Class A ☐ Class A	Class B Class B
☐ EN 50081-2:1993 ☐ EN 61000-6-4:2001	☐ Class A ☐ Class A	☐ Class B ☐ Class B
☐ EN 50083-2:2001		
☐ EN 55011:1998 +A1:1999	☐ Group 1 ☐ Class A	Group 2 Class B
☐ EN 55013:1990 +A12:1994 +A13:1996 +A ☐ EN 55013:2001	<b>\14:1999</b>	
☐ EN 55014-1:2000 ☐ EN 55014-1:2000 +A1:2001		
☐ EN 55015:2000 ☐ EN 55015:2000 +A1:2001		
☐ EN 55022:1994 +A1:1995 +A2:1997 ☐ EN 55022:1998 ☐ EN 55022:1998 +A1:2000	☐ Class A ☐ Class A ☐ Class A	☐ Class B ☐ Class B ☐ Class B
☐ EN 61000-3-2:1995 +A1:1998 +A2:1998 ☐ EN 61000-3-2:2000	+A14:2000	
☐ EN 61000-3-3:1995 ☐ EN 61000-3-3:1995 +A1:2001		
☐ VCCI V-3/2003.04	☐ Class A	☐ Class B
☐ AS/NZS 3548:1995 +A1:1997 +A2:1997	☐ Class A	☐ Class B
	☐ Class A	
☐ CISPR 22:1997 The unit was tested to CISPR 22 and complied FCC under paragraphs 15.107 and 15.109.	☐ Class A with the alternate meth	☐ Class B nods allowed by
CISPR 22:1997 +A1:2000	☐ Class A	☐ Class B

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## 2.1 Conducted Voltage Emissions

#### **Test Date**

May 26, 2004

#### **Test Location**

EMI-CE: Shielded Room

LIMI-CE. Shielded Room			
<b>Test Instruments</b> ☑ Field Strength Meter	Rohde & Schwarz	ESHS30	828144/002
Test Accessories			
	EMCO	3825/2	9409-2246
□ LISN	EMCO	3825/2	9607-2574
☐ Control PC	HP	Vectra 500	SG72000192
Frequency Range of Me	easurement		
☐ 450 kHz to 30 MHz  Instrument Settings			

#### **Test Results**

The requirements are:

IF Band Width: 9 kHz

	minimum margin is 6.4 dBuV (ave	erage)at 0.49 M	1Hz
■ NOT MET	limit exceeded by maximum of	dBuV at	MHz
☐ NOT APPLICABLE			

#### Remarks

See Appendix A for test data.

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#### 2.2 Radiated Electric Field Emissions

<b>Test Date</b> May 26, 2004			
<b>Test Location</b> ⊠ EMI-OATS: Testing was □ EMI-OATS: Testing was	performed at a test of performed at a test of the performance at a tes	listance of 10 m listance of 3 m	
<b>Test Instruments</b> ☑ Field Strength Meter	Rohde & Schwarz	z ESVS30	826638/008
Test Accessories   ☐ ULTRA Broadband Anter  ☐ Bi-conical Antenna  ☐ Bi-conical Antenna  ☐ Log-periodic Antenna  Frequency Range of M	Schwarzbeck EMCO EMCO	BBA9106 3110B	41-00201
30 MHz to 2 GHz			
Instrument Settings IF Band Width: 120 kHz			
<b>Test Results</b> The requirements are:			
	nimum margin is 3.4 o it exceeded by maxim		

See Appendix A for test data

**Remarks** 

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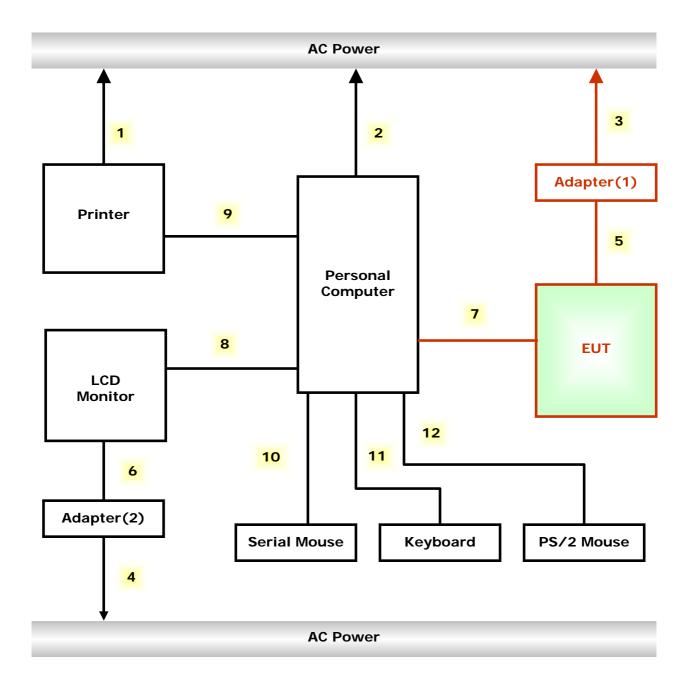
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## Configuration



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#### APPENDIX A - TEST DATA

#### **Conducted Voltage Emissions (Quasi-Peak reading)**

Frequency	Frequency Correction Quasi-peak		Correction				Average				
	Fac	tor	Line	Limit	Reading	Result	Margin	Limit	Reading	Result	Margin
[MHz]	LISN	Cable		[dBuV]	[dBuV]	[dBuV]	[dB]	[dBuV]	[dBuV]	[dBuV]	[dB]
0.49	0.5	0.1	L	56.2	42.0	42.6	13.6	46.2	39.2	39.8	6.4
0.59	0.5	0.1	N	56.0	38.3	38.9	17.1	46.0	36.0	36.6	9.4
1.38	0.3	0.1	L	56.0	39.8	40.2	15.8	46.0	37.6	38.0	8.0
2.26	0.3	0.1	L	56.0	38.9	39.3	16.7	46.0	37.1	37.5	8.5
2.36	0.3	0.1	N	56.0	38.5	38.9	17.1	46.0	36.2	36.6	9.4
3.15	0.3	0.1	L	56.0	39.8	40.2	15.8	46.0	37.6	38.0	8.0
7.47	0.3	0.2	L	60.0	40.4	40.9	19.1	50.0	38.0	38.5	11.5

<sup>\*</sup> If the average limit is met when a quasi-peak detector is used, the EUT shall be deemed to meet both limit and measurement with the average detector is unnecessary.

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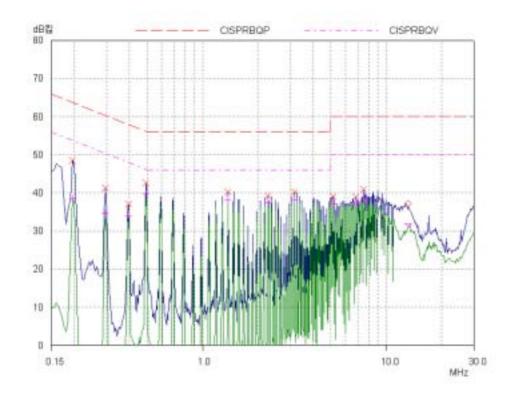
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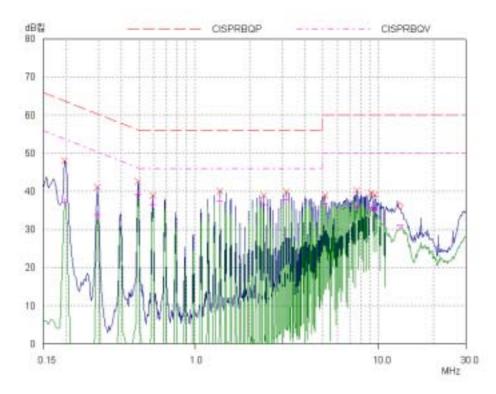
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## Radiated Electric Field Emissions (Quasi-Peak reading)

Frequency	Reading	Pol.	Height	Correction Factor		Limits	Result	Margin
[MHz]	[dBuV/m]		[m]	Antenna	Cable	[dBuV/m]	[dBuV/m]	[dB]
192.04	15.1	V	1.0	7.0	2.7	30.0	24.8	5.2
199.42	16.7	Н	4.0	7.2	2.7	30.0	26.6	3.4
297.35	12.3	Н	4.0	10.9	3.6	37.0	26.8	10.2
480.33	12.3	V	1.0	15.2	4.4	37.0	31.9	5.1
497.83	12.6	Н	3.1	15.6	4.7	37.0	32.9	4.1
513.54	12.3	V	1.0	15.7	4.8	37.0	32.8	4.2
721.81	7.2	V	2.0	18.8	5.9	37.0	31.9	5.1
756.84	7.5	V	1.5	19.0	6.1	37.0	32.6	4.4
865.31	6.4	V	1.0	20.2	6.6	37.0	33.2	3.9

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